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The considered design of BIST will achieve a test,time reduction, a simple test environment and high,parallelism in probing, reducing total of test cost for VC,integration.,1] S. Tanoi, et al., ISSCC 97 Digest, pp. 70-71, 1997,2] J. Dreibelbis, et al., ISSCC 98 Digest., pp. 74-75, 1998,Proceedings of the Proceedings International Test ...

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